

E.U.T. SUPERVISORY UNIT

ESU 04

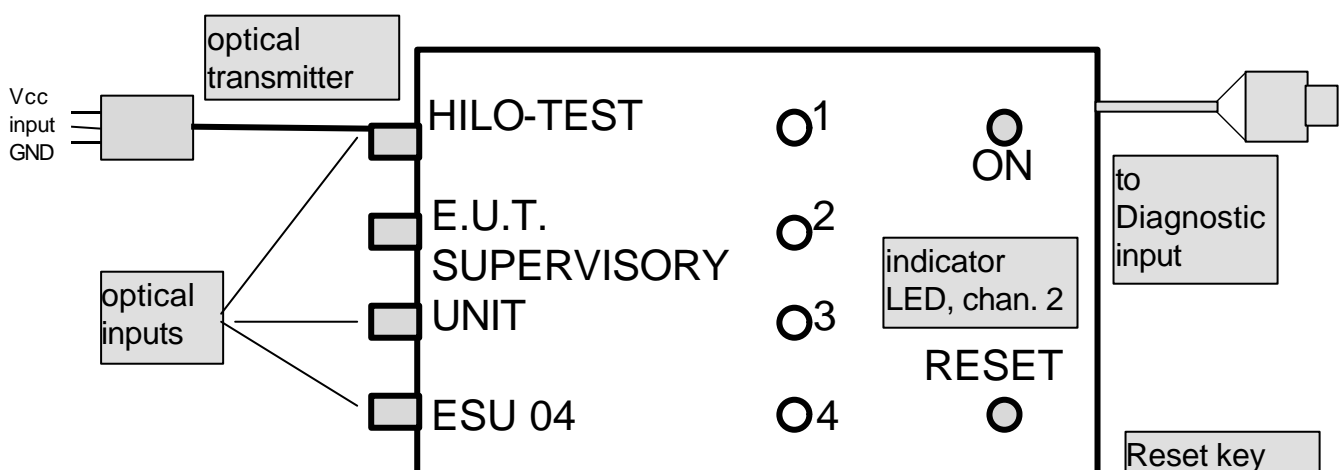
The performance of the Equipment Under Test, E.U.T., during testing electromagnetic compatibility is of crucial significance to the result of the EMC test.

In order to find out the reason of a disturbance of the E.U.T., electrical measurements with voltage probes are not applicable. Connecting the measuring equipment to the E.U.T will significantly decrease the immunity of the E.U.T.

The E.U.T. SUPERVISORY UNIT, ESU 04, solves this problem:

Logical informations of the E.U.T. are captured with Sensors and are transmitted to the Supervisory unit ESU 04 by light guide. Information is stored by flip-flops and transferred to the diagnostic input of the test generator.

Using fibre optic link there is no galvanic connection to the E.U.T.. Supervising the E.U.T. is non-reactive. Connecting the ESU 04 does not influence the immunity of the E.U.T..



The supervisory unit ESU 04 has 4 independent optical inputs. While receiving a light pulse a flip-flop is set and the information is stored. Logical state of the flip-flops is indicated by LED's. Flip-flop outputs are connected to the diagnostic input of the test generator. The diagnostic input of the test generator is read-out after each test sequence, the result is displayed in the test protocol. After read-out the flip-flops are resetted.

Capturing logical information of the E.U.T. is accomplished by sensors with optical transmitter output. Sensors for supervising LOW and HIGH levels are available for different logic families, CMOS, HC AC, TTL etc. The sensors are connected directly to the circuit supervised. They are supplied from the same power supply voltage.

Moreover it is possible to connect any other, user specific sensor to the supervisory unit ESU 04.